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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

E·XFI

Product Status	Not For New Designs
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	107
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	40K × 8
Voltage - Supply (Vcc/Vdd)	4.5V ~ 5.5V
Data Converters	A/D 26x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/spc560p50l5beaay

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

For high priority interrupt requests, the time from the assertion of the interrupt request from the peripheral to when the processor is executing the interrupt service routine (ISR) has been minimized. The INTC provides a unique vector for each interrupt request source for quick determination of which ISR has to be executed. It also provides a wide number of priorities so that lower priority ISRs do not delay the execution of higher priority ISRs. To allow the appropriate priorities for each source of interrupt request, the priority of each interrupt request is software configurable.

When multiple tasks share a resource, coherent accesses to that resource need to be supported. The INTC supports the priority ceiling protocol (PCP) for coherent accesses. By providing a modifiable priority mask, the priority can be raised temporarily so that all tasks which share the same resource can not preempt each other.

The INTC provides the following features:

- Unique 9-bit vector for each separate interrupt source
- 8 software triggerable interrupt sources
- 16 priority levels with fixed hardware arbitration within priority levels for each interrupt source
- Ability to modify the ISR or task priority: modifying the priority can be used to implement the Priority Ceiling Protocol for accessing shared resources.
- 2 external high priority interrupts directly accessing the main core and I/O processor (IOP) critical interrupt mechanism

1.5.7 System status and configuration module (SSCM)

The system status and configuration module (SSCM) provides central device functionality.

The SSCM includes these features:

- System configuration and status
 - Memory sizes/status
 - Device mode and security status
 - Determine boot vector
 - Search code flash for bootable sector
 - DMA status
- Debug status port enable and selection
- Bus and peripheral abort enable/disable

1.5.8 System clocks and clock generation

The following list summarizes the system clock and clock generation on the SPC560P44Lx, SPC560P50Lx:

- Lock detect circuitry continuously monitors lock status
- Loss of clock (LOC) detection for PLL outputs
- Programmable output clock divider (÷1, ÷2, ÷4, ÷8)
- FlexPWM module and eTimer module can run on an independent clock source
- On-chip oscillator with automatic level control
- Internal 16 MHz RC oscillator for rapid start-up and safe mode: supports frequency trimming by user application



1.5.9 Frequency-modulated phase-locked loop (FMPLL)

The FMPLL allows the user to generate high speed system clocks from a 4–40 MHz input clock. Further, the FMPLL supports programmable frequency modulation of the system clock. The PLL multiplication factor, output clock divider ratio are all software configurable.

The PLL has the following major features:

- Input clock frequency: 4–40 MHz
- Maximum output frequency: 64 MHz
- Voltage controlled oscillator (VCO)—frequency 256–512 MHz
- Reduced frequency divider (RFD) for reduced frequency operation without forcing the PLL to relock
- Frequency-modulated PLL
 - Modulation enabled/disabled through software
 - Triangle wave modulation
- Programmable modulation depth (±0.25% to ±4% deviation from center frequency): programmable modulation frequency dependent on reference frequency
- Self-clocked mode (SCM) operation

1.5.10 Main oscillator

The main oscillator provides these features:

- Input frequency range: 4–40 MHz
- Crystal input mode or oscillator input mode
- PLL reference

1.5.11 Internal RC oscillator

This device has an RC ladder phase-shift oscillator. The architecture uses constant current charging of a capacitor. The voltage at the capacitor is compared by the stable bandgap reference voltage.

The RC oscillator provides these features:

- Nominal frequency 16 MHz
- ±5% variation over voltage and temperature after process trim
- Clock output of the RC oscillator serves as system clock source in case loss of lock or loss of clock is detected by the PLL
- RC oscillator is used as the default system clock during startup

1.5.12 Periodic interrupt timer (PIT)

The PIT module implements these features:

- 4 general purpose interrupt timers
- 32-bit counter resolution
- Clocked by system clock frequency
- Each channel can be used as trigger for a DMA request



The SIU provides the following features:

- Centralized general purpose input output (GPIO) control of as many as 80 input/output pins and 26 analog input-only pads (package dependent)
- All GPIO pins can be independently configured to support pull-up, pull down, or no pull
- Reading and writing to GPIO supported both as individual pins and 16-bit wide ports
- All peripheral pins (except ADC channels) can be alternatively configured as both general purpose input or output pins
- ADC channels support alternative configuration as general purpose inputs
- Direct readback of the pin value is supported on all pins through the SIUL
- Configurable digital input filter that can be applied to some general purpose input pins for noise elimination: as many as 4 internal functions can be multiplexed onto 1 pin

1.5.17 Boot and censorship

Different booting modes are available in the SPC560P44Lx, SPC560P50Lx: booting from internal flash memory and booting via a serial link.

The default booting scheme uses the internal flash memory (an internal pull-down is used to select this mode). Optionally, the user can boot via FlexCAN or LINFlex (using the boot assist module software).

A censorship scheme is provided to protect the content of the flash memory and offer increased security for the entire device.

A password mechanism is designed to grant the legitimate user access to the non-volatile memory.

Boot assist module (BAM)

The BAM is a block of read-only one-time programmed memory and is identical for all SPC560Pxx devices that are based on the e200z0h core. The BAM program is executed every time the device is powered on if the alternate boot mode has been selected by the user.

The BAM provides the following features:

- Serial bootloading via FlexCAN or LINFlex
- Ability to accept a password via the used serial communication channel to grant the legitimate user access to the non-volatile memory

1.5.18 Error correction status module (ECSM)

The ECSM provides a myriad of miscellaneous control functions regarding program-visible information about the platform configuration and revision levels, a reset status register, a software watchdog timer, wakeup control for exiting sleep modes, and information on platform memory errors reported by error-correcting codes and/or generic access error information for certain processor cores.

The Error Correction Status Module supports a number of miscellaneous control functions for the platform. The ECSM includes these features:

- Registers for capturing information on platform memory errors if error-correcting codes (ECC) are implemented
- For test purposes, optional registers to specify the generation of double-bit memory errors are enabled on the SPC560P44Lx, SPC560P50Lx.



1.5.22 FlexRay

The FlexRay module provides the following features:

- Full implementation of FlexRay Protocol Specification 2.1
- 32 configurable message buffers can be handled
- Dual channel or single channel mode of operation, each as fast as 10 Mbit/s data rate
- Message buffers configurable as Tx, Rx or RxFIFO
- Message buffer size configurable
- Message filtering for all message buffers based on FrameID, cycle count and message ID
- Programmable acceptance filters for RxFIFO message buffers

1.5.23 Serial communication interface module (LINFlex)

The LINFlex (local interconnect network flexible) on the SPC560P44Lx, SPC560P50Lx features the following:

- Supports LIN Master mode, LIN Slave mode and UART mode
- LIN state machine compliant to LIN1.3, 2.0, and 2.1 specifications
- Handles LIN frame transmission and reception without CPU intervention
- LIN features
 - Autonomous LIN frame handling
 - Message buffer to store Identifier and as much as 8 data bytes
 - Supports message length as long as 64 bytes
 - Detection and flagging of LIN errors (sync field, delimiter, ID parity, bit framing, checksum, and time-out)
 - Classic or extended checksum calculation
 - Configurable Break duration as long as 36-bit times
 - Programmable baud rate prescalers (13-bit mantissa, 4-bit fractional)
 - Diagnostic features: Loop back; Self Test; LIN bus stuck dominant detection
 - Interrupt-driven operation with 16 interrupt sources
- LIN slave mode features
 - Autonomous LIN header handling
 - Autonomous LIN response handling
- UART mode
 - Full-duplex operation
 - Standard non return-to-zero (NRZ) mark/space format
 - Data buffers with 4-byte receive, 4-byte transmit
 - Configurable word length (8-bit or 9-bit words)
 - Error detection and flagging
 - Parity, Noise and Framing errors
 - Interrupt-driven operation with four interrupt sources
 - Separate transmitter and receiver CPU interrupt sources
 - 16-bit programmable baud-rate modulus counter and 16-bit fractional
 - 2 receiver wake-up methods



1.5.24 Deserial serial peripheral interface (DSPI)

The deserial serial peripheral interface (DSPI) module provides a synchronous serial interface for communication between the SPC560P44Lx, SPC560P50Lx MCU and external devices.

The DSPI modules provide these features:

- Full duplex, synchronous transfers
- Master or slave operation
- Programmable master bit rates
- Programmable clock polarity and phase
- End-of-transmission interrupt flag
- Programmable transfer baud rate
- Programmable data frames from 4 to 16 bits
- Up to 20 chip select lines available
 - 8 on DSPI_0
 - 4 each on DSPI_1, DSPI_2 and DSPI_3
- 8 clock and transfer attributes registers
- Chip select strobe available as alternate function on one of the chip select pins for deglitching
- FIFOs for buffering as many as 5 transfers on the transmit and receive side
- Queueing operation possible through use of the eDMA
- General purpose I/O functionality on pins when not used for SPI

1.5.25 Pulse width modulator (FlexPWM)

The pulse width modulator module (PWM) contains four PWM submodules, each capable of controlling a single half-bridge power stage. There are also four fault channels.

This PWM is capable of controlling most motor types: AC induction motors (ACIM), permanent magnet AC motors (PMAC), both brushless (BLDC) and brush DC motors (BDC), switched (SRM) and variable reluctance motors (VRM), and stepper motors.



1.5.26 eTimer

The SPC560P44Lx, SPC560P50Lx includes two eTimer modules. Each module provides six 16-bit general purpose up/down timer/counter units with the following features:

- Maximum operating clock frequency of 120 MHz
- Individual channel capability
 - Input capture trigger
 - Output compare
 - Double buffer (to capture rising edge and falling edge)
 - Separate prescaler for each counter
 - Selectable clock source
 - 0–100% pulse measurement
 - Rotation direction flag (Quad decoder mode)
- Maximum count rate
 - External event counting: max. count rate = peripheral clock/2
 - Internal clock counting: max. count rate = peripheral clock
- Counters are:
 - Cascadable
 - Preloadable
- Programmable count modulo
- Quadrature decode capabilities
- Counters can share available input pins
- Count once or repeatedly
- Pins available as GPIO when timer functionality not in use

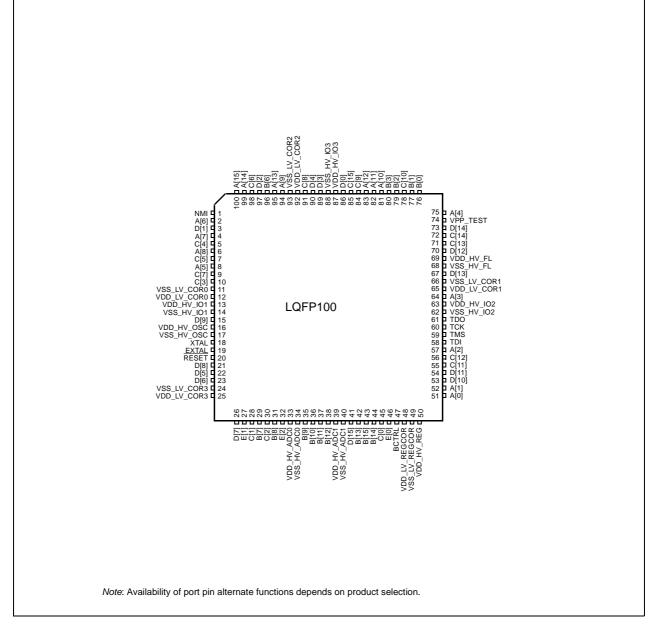
1.5.27 Analog-to-digital converter (ADC) module

The ADC module provides the following features:

Analog part:

- 2 on-chip AD converters
 - 10-bit AD resolution
 - 1 sample and hold unit per ADC
 - Conversion time, including sampling time, less than 1 µs (at full precision)
 - Typical sampling time is 150 ns min. (at full precision)
 - Differential non-linearity error (DNL) ±1 LSB
 - Integral non-linearity error (INL) ±1.5 LSB
 - TUE <3 LSB
 - Single-ended input signal up to 5.0 V
 - The ADC and its reference can be supplied with a voltage independent from V_{DDIO}
 - The ADC supply can be equal or higher than V_{DDIO}
 - The ADC supply and the ADC reference are not independent from each other (they are internally bonded to the same pad)
 - Sample times of 2 (default), 8, 64, or 128 ADC clock cycles







2.2 Pin description

The following sections provide signal descriptions and related information about the functionality and configuration of the SPC560P44Lx, SPC560P50Lx devices.

2.2.1 Power supply and reference voltage pins

Table 5 lists the power supply and reference voltage for the SPC560P44Lx, SPC560P50Lx devices.



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Table 7.	Pin r	nuxing
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Port	Pad	Alternate			I/O	Pad s	peed ⁽⁵⁾	Pin	No.
pin	configuration register (PCR)	function ^{(1),} (2)	Functions	Peripheral ⁽³⁾	direction (4)	SRC = 0	SRC = 1	100-pin	144-pin
				Port A (16-bit)					
A[0]	PCR[0]	ALTO ALT1 ALT2 ALT3 —	GPIO[0] ETC[0] SCK F[0] EIRQ[0]	SIUL eTimer_0 DSPI_2 FCU_0 SIUL	I/O I/O O I	Slow	Medium	51	73
A[1]	PCR[1]	ALTO ALT1 ALT2 ALT3 —	GPIO[1] ETC[1] SOUT F[1] EIRQ[1]	SIUL eTimer_0 DSPI_2 FCU_0 SIUL	I/O I/O O I	Slow	Medium	52	74
A[2] ⁽⁶⁾	PCR[2]	ALT0 ALT1 ALT2 ALT3 — — —	GPIO[2] ETC[2] — A[3] SIN ABS[0] EIRQ[2]	SIUL eTimer_0 — FlexPWM_0 DSPI_2 MC_RGM SIUL	I/O I/O - O I I I	Slow	Medium	57	84
A[3] ⁽⁶⁾	PCR[3]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[3] ETC[3] CS0 B[3] ABS[2] EIRQ[3]	SIUL eTimer_0 DSPI_2 FlexPWM_0 MC_RGM SIUL	I/O I/O I/O O I I	Slow	Medium	64	92
A[4] ⁽⁶⁾	PCR[4]	ALT0 ALT1 ALT2 ALT3 — —	GPIO[4] ETC[0] CS1 ETC[4] FAB EIRQ[4]	SIUL eTimer_1 DSPI_2 eTimer_0 MC_RGM SIUL	I/O I/O O I/O I I	Slow	Medium	75	108
A[5]	PCR[5]	ALTO ALT1 ALT2 ALT3 —	GPIO[5] CS0 ETC[5] CS7 EIRQ[5]	SIUL DSPI_1 eTimer_1 DSPI_0 SIUL	I/O I/O I/O I	Slow	Medium	8	14
A[6]	PCR[6]	ALTO ALT1 ALT2 ALT3 —	GPIO[6] SCK — — EIRQ[6]	SIUL DSPI_1 — SIUL	I/O I/O — I	Slow	Medium	2	2



Port	Pad	Alternate			I/O	Pad s	d speed ⁽⁵⁾		No.
pin	configuration register (PCR)	(0)	Functions	Peripheral ⁽³⁾	direction (4)	SRC = 0	SRC = 1	100-pin	144-pin
		ALT0	GPIO[14]	SIUL	I/O				
		ALT1	TXD	Safety Port_0	0				
A[14]	PCR[14]	ALT2	ETC[4]	eTimer_1	I/O	Slow	Medium	99	143
		ALT3	—	—	—				
		—	EIRQ[13]	SIUL	I				
		ALT0	GPIO[15]	SIUL	I/O				
		ALT1	—	—	—				
A[15]	PCR[15]	ALT2	ETC[5]	eTimer_1	I/O	Slow	Medium	100	144
A[15]	FCR[15]	ALT3	—	—	—	310W	Medium	100	144
		—	RXD	Safety Port_0	I				
		—	EIRQ[14]	SIUL	I				
				Port B (16-bit)					
		ALT0	GPIO[16]	SIUL	I/O				
		ALT1	TXD	FlexCAN_0	0				
B[0]	PCR[16]	ALT2	ETC[2]	eTimer_1	I/O	Slow	Medium	76	109
		ALT3	DEBUG[0]	SSCM	—				
		—	EIRQ[15]	SIUL	I				
		ALT0	GPIO[17]	SIUL	I/O				
		ALT1	—	—	—				
B[1]	PCR[17]	ALT2	ETC[3]	eTimer_1	I/O	Slow	Medium	77	110
D[1]	FOR[17]	ALT3	DEBUG[1]	SSCM	—	310W	Medium	11	110
		—	RXD	FlexCAN_0	I				
		—	EIRQ[16]	SIUL	I				
		ALT0	GPIO[18]	SIUL	I/O				
		ALT1	TXD	LIN_0	0				
B[2]	PCR[18]	ALT2	—	—	—	Slow	Medium	79	114
		ALT3	DEBUG[2]	SSCM	—				
		—	EIRQ[17]	SIUL	I				
		ALT0	GPIO[19]	SIUL	I/O				
		ALT1	—	—	—				
B[3]	PCR[19]	ALT2	—	—	—	Slow	Medium	80	116
		ALT3	DEBUG[3]	SSCM	—				
		—	RXD	LIN_0	I				
		ALT0	GPIO[22]	SIUL	I/O				
		ALT1	CLKOUT	MC_CGL	0				
B[6]	PCR[22]	ALT2	CS2	DSPI_2	0	Slow	Medium	96	138
		ALT3	—	—	—				
		—	EIRQ[18]	SIUL	I				

Table 7. Pin muxing (continued)



Port	Pad	Alternate			I/O	Pad s	peed ⁽⁵⁾	Pin	No.
pin	configuration register (PCR)	(0)	Functions	Peripheral ⁽³⁾	direction (4)	SRC = 0	SRC = 1	100-pin	144-pin
C[5]	ALT1 SCK DSPI_0 I		I/O I/O — I I	Slow	Medium	7	13		
C[6]	PCR[38]	ALTO ALT1 ALT2 ALT3 —	GPIO[38] SOUT B[1] DEBUG[6] EIRQ[24]	SIUL DSPI_0 FlexPWM_0 SSCM SIUL	I/O I/O O I	Slow	Medium	98	142
C[7]	PCR[39]	ALT0 ALT1 ALT2 ALT3 —	GPIO[39] — A[1] DEBUG[7] SIN	SIUL — FlexPWM_0 SSCM DSPI_0	I/O — — — —	Slow	Medium	9	15
C[8]	PCR[40]	ALTO ALT1 ALT2 ALT3 —	GPIO[40] CS1 — CS6 FAULT[2]	SIUL DSPI_1 — DSPI_0 FlexPWM_0	I/O O — O I	Slow	Medium	91	130
C[9]	PCR[41]	ALTO ALT1 ALT2 ALT3 —	GPIO[41] CS3 — X[3] FAULT[2]	SIUL DSPI_2 — FlexPWM_0 FlexPWM_0	I/O O — I/O I	Slow	Medium	84	123
C[10]	PCR[42]	ALTO ALT1 ALT2 ALT3 —	GPIO[42] CS2 — A[3] FAULT[1]	SIUL DSPI_2 — FlexPWM_0 FlexPWM_0	I/O O — O I	Slow	Medium	78	111
C[11]	PCR[43]	ALTO ALT1 ALT2 ALT3	GPIO[43] ETC[4] CS2 CS0	SIUL eTimer_0 DSPI_2 DSPI_3	I/O I/O O I/O	Slow	Medium	55	80
C[12]	PCR[44]	ALTO ALT1 ALT2 ALT3	GPIO[44] ETC[5] CS3 CS1	SIUL eTimer_0 DSPI_2 DSPI_3	I/O I/O O O	Slow	Medium	56	82

 Table 7.
 Pin muxing (continued)



Port	Pad	Alternate			I/O	/O Pad speed ⁽⁵⁾			Pin No.		
pin	configuration register (PCR)	(0)	Functions	Peripheral ⁽³⁾	direction (4)	SRC = 0	SRC = 1	100-pin	144-pin		
E[5]	PCR[69]	ALT0 ALT1 ALT2 ALT3 —	GPIO[69] — — AN[8]	SIUL — — ADC_0	Input only	_	_	_	44		
E[6]	PCR[70]	ALT0 ALT1 ALT2 ALT3 —	GPIO[70] — — — AN[9]	SIUL — — — ADC_0	Input only		_	_	46		
E[7]	PCR[71]	ALTO ALT1 ALT2 ALT3 —	GPIO[71] — — — AN[10]	SIUL — — — ADC_0	Input only	_	_	_	48		
E[8]	PCR[72]	ALTO ALT1 ALT2 ALT3 —	GPIO[72] — — — AN[6]	SIUL — — — ADC_1	Input only	_	_	_	59		
E[9]	PCR[73]	ALTO ALT1 ALT2 ALT3 —	GPIO[73] — — — AN[7]	SIUL — — ADC_1	Input only	_	_	_	61		
E[10]	PCR[74]	ALT0 ALT1 ALT2 ALT3 —	GPIO[74] — — — AN[8]	SIUL — — — ADC_1	Input only	-	_	_	63		
E[11]	PCR[75]	ALT0 ALT1 ALT2 ALT3 —	GPIO[75] — — — AN[9]	SIUL — — — ADC_1	Input only	_	_	_	65		
E[12]	PCR[76]	ALT0 ALT1 ALT2 ALT3 —	GPIO[76] — — — AN[10]	SIUL — — — ADC_1	Input only	_	_	_	67		

Table 7. Pin muxing (continued)



3 Electrical characteristics

3.1 Introduction

This section contains device electrical characteristics as well as temperature and power considerations.

This microcontroller contains input protection against damage due to high static voltages. However, it is advisable to take precautions to avoid application of any voltage higher than the specified maximum rated voltages.

To enhance reliability, unused inputs can be driven to an appropriate logic voltage level (V_{DD} or V_{SS}). This can be done by the internal pull-up or pull-down resistors, which are provided by the device for most general purpose pins.

The following tables provide the device characteristics and its demands on the system.

In the tables where the device logic provides signals with their respective timing characteristics, the symbol "CC" for Controller Characteristics is included in the Symbol column.

In the tables where the external system must provide signals with their respective timing characteristics to the device, the symbol "SR" for System Requirement is included in the Symbol column.

Caution: All of the following parameter values can vary depending on the application and must be confirmed during silicon characterization or silicon reliability trial.

3.2 Parameter classification

The electrical parameters are guaranteed by various methods. To give the customer a better understanding, the classifications listed in *Table 8* are used and the parameters are tagged accordingly in the tables where appropriate.

Classification tag Tag description		
Р	Those parameters are guaranteed during production testing on each individual device.	
С	Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations.	
т	Those parameters are achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted. All values shown in the typical column are within this category.	
D	Those parameters are derived mainly from simulations.	

Table 8.Parameter classifications

Note: The classification is shown in the column labeled "C" in the parameter tables where appropriate.



- C.E. Triplett and B. Joiner, An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module, Proceedings of SemiTherm, San Diego, 1998, pp. 47–54.
- 2. G. Kromann, S. Shidore, and S. Addison, *Thermal Modeling of a PBGA for Air-Cooled Applications*, Electronic Packaging and Production, pp. 53–58, March 1998.
- 3. B. Joiner and V. Adams, *Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling*, Proceedings of SemiTherm, San Diego, 1999, pp. 212–220.

3.6 Electromagnetic interference (EMI) characteristics

Symbol	Parameter	Conditions	Clocks	Frequency	Level (Max)	Unit
		Device configuration test		150 kHz–150 MHz	16	dBµV
		conditions and EM testing per standard IEC61967-2 Supply voltage = 5 V DC Ambient temperature = 25 °C Worst-case orientation	f _{CPU} 64 MHz No PLL frequency	150–1000 MHz	15	uυμν
V	Radiated emissions		modulation	IEC Level	М	—
V _{EME}			f _{OSC} 8 MHz f _{CPU} 64 MHz	150 kHz–150 MHz	15	dBµV
				150–1000 MHz	14	ubµv
			1% PLL frequency modulation	IEC Level	М	—

Table 14. EMI testing specifications

3.7 Electrostatic discharge (ESD) characteristics

Table 15.ESD ratings^{(1),(2)}

Symbol		Parameter	Conditions	Value	Unit
V _{ESD(HBM)}	S R	Electrostatic discharge (Human Body Model)	_	2000	V
	s	Electrostatic discharge (Charged Device Model)		750 (corners)	v
VESD(CDM)	R	Electrostatic discharge (Charged Device Model)	_	500 (other)	v

1. All ESD testing is in conformity with CDF-AEC-Q100 Stress Test Qualification for Automotive Grade Integrated Circuits.

2. A device will be defined as a failure if after exposure to ESD pulses the device no longer meets the device specification requirements. Complete DC parametric and functional testing shall be performed per applicable device specification at room temperature followed by hot temperature, unless specified otherwise in the device specification.

3.8 Power management electrical characteristics

3.8.1 Voltage regulator electrical characteristics

The internal voltage regulator requires an external NPN ballast to be connected as shown in *Figure 9. Table 16* contains all approved NPN ballast components. Capacitances should be placed on the board as near as possible to the associated pins. Care should also be taken to limit the serial inductance of the V_{DD HV REG}, BCTRL and V_{DD LV CORx} pins to less than



3.10.2 DC electrical characteristics (5 V)

Table 21 gives the DC electrical characteristics at 5 V (4.5 V < $V_{DD_HV_IOx}$ < 5.5 V, NVUSRO[PAD3V5V] = 0); see *Figure 14*.

Symbol		Denemeter	Conditions	V	alue	11
Symbol	С	Parameter	Conditions	Min	Max	Unit
M	D		—	-0.1 ⁽¹⁾	—	V
V _{IL}	Ρ	Low level input voltage		—	0.35 V _{DD_HV_IOx}	V
V	Ρ	High level input voltage	—	0.65 V _{DD_HV_IOx}	—	V
V _{IH}	D	nigh level input voltage	—	—	$V_{\text{DD}_\text{HV}_\text{IOx}} + 0.1^{(1)}$	V
V _{HYS}	Т	Schmitt trigger hysteresis	—	0.1 V _{DD_HV_IOx}	—	V
V _{OL_S}	Ρ	Slow, low level output voltage	I _{OL} = 3 mA	—	0.1 V _{DD_HV_IOx}	V
V _{OH_S}	Ρ	Slow, high level output voltage	I _{OH} = -3 mA	0.8 V _{DD_HV_IOx}	—	V
V _{OL_M}	Ρ	Medium, low level output voltage	I _{OL} = 3 mA	—	0.1 V _{DD_HV_IOx}	V
V _{OH_M}	Ρ	Medium, high level output voltage	I _{OH} = -3 mA	0.8 V _{DD_HV_IOx}	—	V
V_{OL_F}	Ρ	Fast, low level output voltage	I _{OL} = 3 mA	—	0.1 V _{DD_HV_IOx}	V
V_{OH_F}	Ρ	Fast, high level output voltage	I _{OH} = -3 mA	0.8 V _{DD_HV_IOx}	—	V
V_{OL_SYM}	Ρ	Symmetric, low level output voltage	I _{OL} = 3 mA	—	0.1 V _{DD_HV_IOx}	V
V_{OH_SYM}	Ρ	Symmetric, high level output voltage	I _{OH} = –3 mA	0.8 V _{DD_HV_IOx}	—	V
	Р	Equivalent pull-up current	$V_{IN} = V_{IL}$	-130	—	μA
I _{PU}	Г	Equivalent pull-up current	$V_{IN} = V_{IH}$	—	-10	μΑ
1	D	Equivalent pull-down current	$V_{IN} = V_{IL}$	10	—	μA
I _{PD}			$V_{IN} = V_{IH}$	—	130	μΛ
IIL	Ρ	Input leakage current (all bidirectional ports)	$T_A = -40$ to 125 °C	-1	1	μA
IIL	Ρ	Input leakage current (all ADC input- only ports)	$T_A = -40$ to 125 °C	-0.5	0.5	μA
C _{IN}	D	Input capacitance	_	—	10	pF
		RESET, equivalent pull-up current	$V_{IN} = V_{IL}$	-130	—	
I _{PU}		RESET, equivalent pull-up current	$V_{IN} = V_{IH}$	—	-10	μA

Table 21.	DC electrical	characteristics	(5 0 V	NVUSRO	- 0)
	Do electrical	characteristics	(J.U V		- 0)

1. "SR" parameter values must not exceed the absolute maximum ratings shown in Table 9.



Table 26.	I/O weight ((continued)
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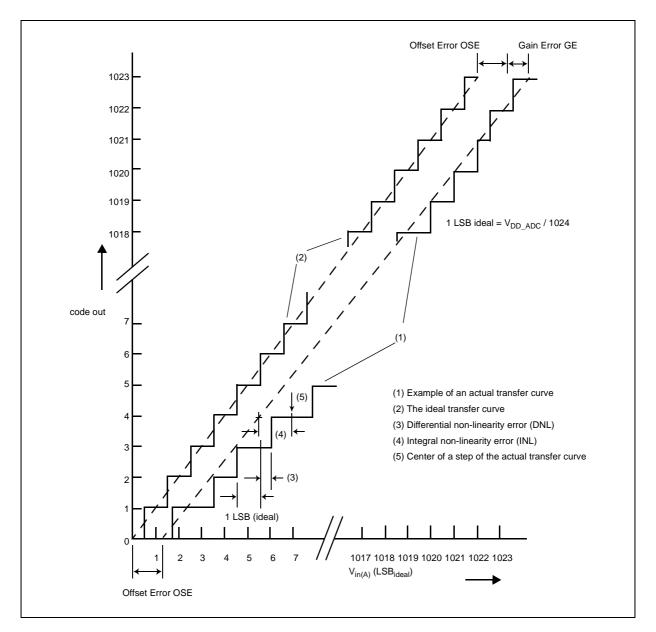
Ded	LQI	FP144	LQFP100		
Pad	Weight 5V	Weight 3.3V	Weight 5V	Weight 3.3V	
PAD[86]	9%	6%	—	_	
MODO[0]	12%	8%	_		
PAD[7]	4%	4%	11%	10%	
PAD[36]	5%	4%	11%	9%	
PAD[8]	5%	4%	10%	9%	
PAD[37]	5%	4%	10%	9%	
PAD[5]	5%	4%	9%	8%	
PAD[39]	5%	4%	9%	8%	
PAD[35]	5%	4%	8%	7%	
PAD[87]	12%	9%	—	_	
PAD[88]	9%	6%	—		
PAD[89]	10%	7%	—	_	
PAD[90]	15%	11%	—	_	
PAD[91]	6%	5%	—	_	
PAD[57]	8%	7%	8%	7%	
PAD[56]	13%	11%	13%	11%	
PAD[53]	14%	12%	14%	12%	
PAD[54]	15%	13%	15%	13%	
PAD[55]	25%	22%	25%	22%	
PAD[96]	27%	24%	—	_	
PAD[65]	1%	1%	1%	1%	
PAD[67]	1%	1%	—	_	
PAD[33]	1%	1%	1%	1%	
PAD[68]	1%	1%	—	_	
PAD[23]	1%	1%	1%	1%	
PAD[69]	1%	1%	—	_	
PAD[34]	1%	1%	1%	1%	
PAD[70]	1%	1%	—	_	
PAD[24]	1%	1%	1%	1%	
PAD[71]	1%	1%	—	_	
PAD[66]	1%	1%	1%	1%	
PAD[25]	1%	1%	1%	1%	
PAD[26]	1%	1%	1%	1%	



Table 26.	I/O weight ((continued)
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Ded	LQI	FP144	LQFP100		
Pad	Weight 5V	Weight 3.3V	Weight 5V	Weight 3.3V	
PAD[60]	11%	10%	11%	10%	
PAD[100]	12%	10%	_	_	
PAD[45]	12%	10%	12%	10%	
PAD[98]	12%	11%	—		
PAD[46]	12%	11%	12%	11%	
PAD[99]	13%	11%	—	_	
PAD[62]	13%	11%	13%	11%	
PAD[92]	13%	12%	_	_	
VPP_TEST	1%	1%	1%	1%	
PAD[4]	14%	12%	14%	12%	
PAD[16]	13%	12%	13%	12%	
PAD[17]	13%	11%	13%	11%	
PAD[42]	13%	11%	13%	11%	
PAD[93]	12%	11%	_		
PAD[95]	12%	11%	_		
PAD[18]	12%	10%	12%	10%	
PAD[94]	11%	10%	_	_	
PAD[19]	11%	10%	11%	10%	
PAD[77]	10%	9%	_	_	
PAD[10]	10%	9%	10%	9%	
PAD[78]	9%	8%	_		
PAD[11]	9%	8%	9%	8%	
PAD[79]	8%	7%	_		
PAD[12]	7%	7%	7%	7%	
PAD[41]	7%	6%	7%	6%	
PAD[47]	5%	4%	5%	4%	
PAD[48]	4%	4%	4%	4%	
PAD[51]	4%	4%	4%	4%	
PAD[52]	5%	4%	5%	4%	
PAD[40]	5%	5%	6%	5%	
PAD[80]	9%	8%	—	_	
PAD[9]	10%	9%	11%	10%	
PAD[81]	10%	9%	_		







3.14.1 Input impedance and ADC accuracy

To preserve the accuracy of the A/D converter, it is necessary that analog input pins have low AC impedance. Placing a capacitor with good high frequency characteristics at the input pin of the device can be effective: the capacitor should be as large as possible, ideally infinite. This capacitor contributes to attenuating the noise present on the input pin; further, it sources charge during the sampling phase, when the analog signal source is a highimpedance source.

A real filter can typically be obtained by using a series resistance with a capacitor on the input pin (simple RC filter). The RC filtering may be limited according to the source impedance value of the transducer or circuit supplying the analog signal to be measured.



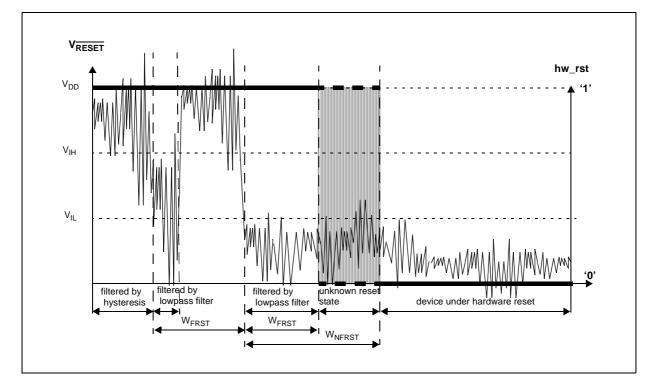


Figure 21. Noise filtering on reset signal

Table 38.	RESET electrical cl	naracteristics
Table 50.		anacteristics

Symbol		с	Parameter	Conditions ⁽¹⁾		Value		Unit	
Symb	01	C	Farameter	Conditions	Min	Тур	Max	Unit	
V _{IH}	SR		Input High Level CMOS (Schmitt Trigger)	—	0.65V _{DD}	_	V _{DD} +0.4	V	
V _{IL}	OIX	Р	Input low Level CMOS (Schmitt Trigger)	_	-0.4		$0.35V_{DD}$	V	
V _{HYS}	сс	С	Input hysteresis CMOS (Schmitt Trigger)	_	0.1V _{DD}		_	V	
				Push Pull, I _{OL} = 2mA, V _{DD} = 5.0 V ± 10%, PAD3V5V = 0 (recommended)	_	_	0.1V _{DD}		
V _{OL} CC	P Output low level	Push Pull, I _{OL} = 1mA, V _{DD} = 5.0 V ± 10%, PAD3V5V = 1 ⁽²⁾	_	_	0.1V _{DD}	V			
						Push Pull, I _{OL} = 1mA, V _{DD} = 3.3 V ± 10%, PAD3V5V = 1 (recommended)		_	0.5



Symbol		с	Deremeter	Conditions ⁽¹⁾		Unit										
		C	Parameter	Conditions	Min	Тур	Max	Unit								
				C _L = 25pF, V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	—	—	10									
t _{tr} CC				C _L = 50pF, V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	_	_	20									
	<u> </u>	П	Output transition time output pin ⁽³⁾	C _L = 100pF, V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	_	_	40	ns								
		MEDIUM configuration	C _L = 25pF, V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	_	—	12	115									
													C _L = 50pF, V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	_	—	25
															C _L = 100pF, V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	_
W _{FRST}	SR	Ρ	RESET input filtered pulse	_	_	_	40	ns								
W _{NFRST}	SR	Ρ	RESET input not filtered pulse	_	500	—	_	ns								
t _{POR}	сс	D	Maximum delay before internal reset is released after all V _{DD_HV} reach nominal supply	Monotonic V _{DD_HV} supply ramp	_	_	1	ms								
				V _{DD} = 3.3 V ± 10%, PAD3V5V = 1	10	—	150									
I _{WPU}	сс	Ρ	Weak pull-up current absolute value	V _{DD} = 5.0 V ± 10%, PAD3V5V = 0	10	_	150	μA								
				V _{DD} = 5.0 V ± 10%, PAD3V5V = 1 ⁽⁴⁾	10	—	250									

Table 38.	RESET electrical characteristics	(continued))

1. V_{DD} = 3.3 V \pm 10% / 5.0 V \pm 10%, T_A = -40 °C to T_A $_{MAX}$, unless otherwise specified

2. This is a transient configuration during power-up, up to the end of reset PHASE2 (refer to RGM module section of device reference manual).

3. C_L includes device and package capacitance (C_{PKG} < 5 pF).

4. The configuration PAD3V5 = 1 when V_{DD} = 5 V is only transient configuration during power-up. All pads but RESET and Nexus output (MDOx, EVTO, MCKO) are configured in input or in high impedance state.

3.17.2 IEEE 1149.1 interface timing

Table 39.	JTAG pin AC electrical characteristics
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No.	o. Symbol (с	Parameter	Conditions	Va	lue	Unit
NO.				Falameter	Conditions	Min	Max	Unit
1	t _{JCYC}	CC	D	TCK cycle time	—	100	—	ns
2	t _{JDC}	CC	D	TCK clock pulse width (measured at $V_{DD_HV_IOX}/2$)	—	40	60	ns
3	t _{TCKRISE}	CC	D	TCK rise and fall times (40% – 70%)	—	—	3	ns
4	t _{TMSS} , t _{TDIS}	CC	D	TMS, TDI data setup time	—	5	—	ns



Date	Revision	Changes
18-Jul-2012	8	Updated Table 1 (Device summary) Section 1.5.4, Flash memory: Changed "Data flash memory: 32-bit ECC" to "Data flash memory: 64-bit ECC" Figure 40 (Commercial product code structure), replaced "C = 60 MHz, 5 V" and "D = 60 MHz, 3.3 V" with respectively "C = 40 MHz, 5 V" and "D = 40 MHz, 3.3 V" Table 9 (Absolute maximum ratings), updated TV _{DD} parameter, the minimum value to 3.0 V/s and the maximum ratings), updated TV _{DD} parameter, the minimum value to 3.0 V/s and the maximum ratings), updated TV _{DD} parameter, the minimum value to 3.0 V/s and the maximum ratings), updated TV _{DD} parameter, the minimum value to 3.0 V/s and the maximum ratings), updated TV _{DD} parameter, the minimum value to 3.0 V/s and the maximum value to 0.5 V/µs Table 7 (Pin muxing), changed the description in the column "I/O direction" from "I/O" to "O" for the following port pins: A[10] with function B[0] A[11] with function A[2] A[12] with function A[2] A[12] with function B[2] C[7] with function A[3] C[15] with function A[1] D[0] with function A[1] D[10] with function A[1] D[11] with function A[1] D[13] with function A[1] D[14] with function A[1] D[15] with function A[1] D[14] with function B[1] Updated Section 3.8.1, Voltage regulator electrical characteristics Added Table 27 (I/O consumption) Section 3.10, DC electrical characteristics: deleted references to "oscillator margin" deleted subsection "NVUSRO[OSCILLATOR_MARGIN] field description" Table 21 (DC electrical characteristics (5.0 V, NVUSRO[PAD3V5V] = 0)), added IPU row for RESET pin Table 23 (DC electrical characteristics), added V _{INAN} entry Removed "Order codes" table Figure 40 (Commercial product code structure): added a footnote updated "E = Data flash memory"
18-Sep-2013	9	Updated Disclaimer

Table 46. Revision history (continued	Table 46.	Revision	history ((continued))
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